

High-Speed DDR4 Memory Designs and Power Integrity Analysis

Cuong Nguyen

Field Application Engineer
cuong@edadirect.com



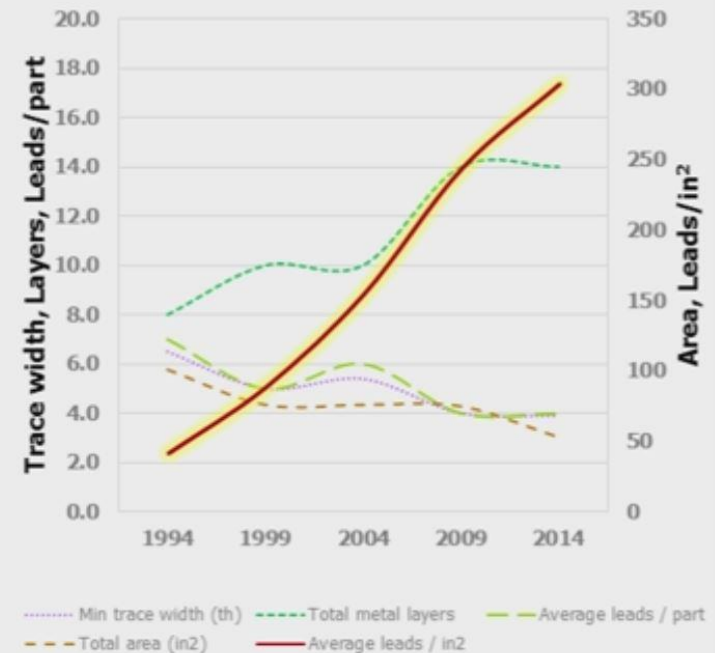
www.edadirect.com



PCB Complexity is Accelerating

Trends in PCB Complexity

Design Trend	1994	2004	2009	2014
Min trace/spacing (th)	6.5/6.5	5.4/5.4	4/4	3.9/4.2
Total metal layers	8	10	14	14
Total area (in ²)	101	76	75	53
# Nets	1465	2952	3411	2109
# Pin-to-pin connections	5190	8813	10960	6228
# Components	649	1981	3400	2608
# Component pins	4214	7760	13505	10122
Leads / part	7	6	5	4
Leads / in ²	42	155	244	304



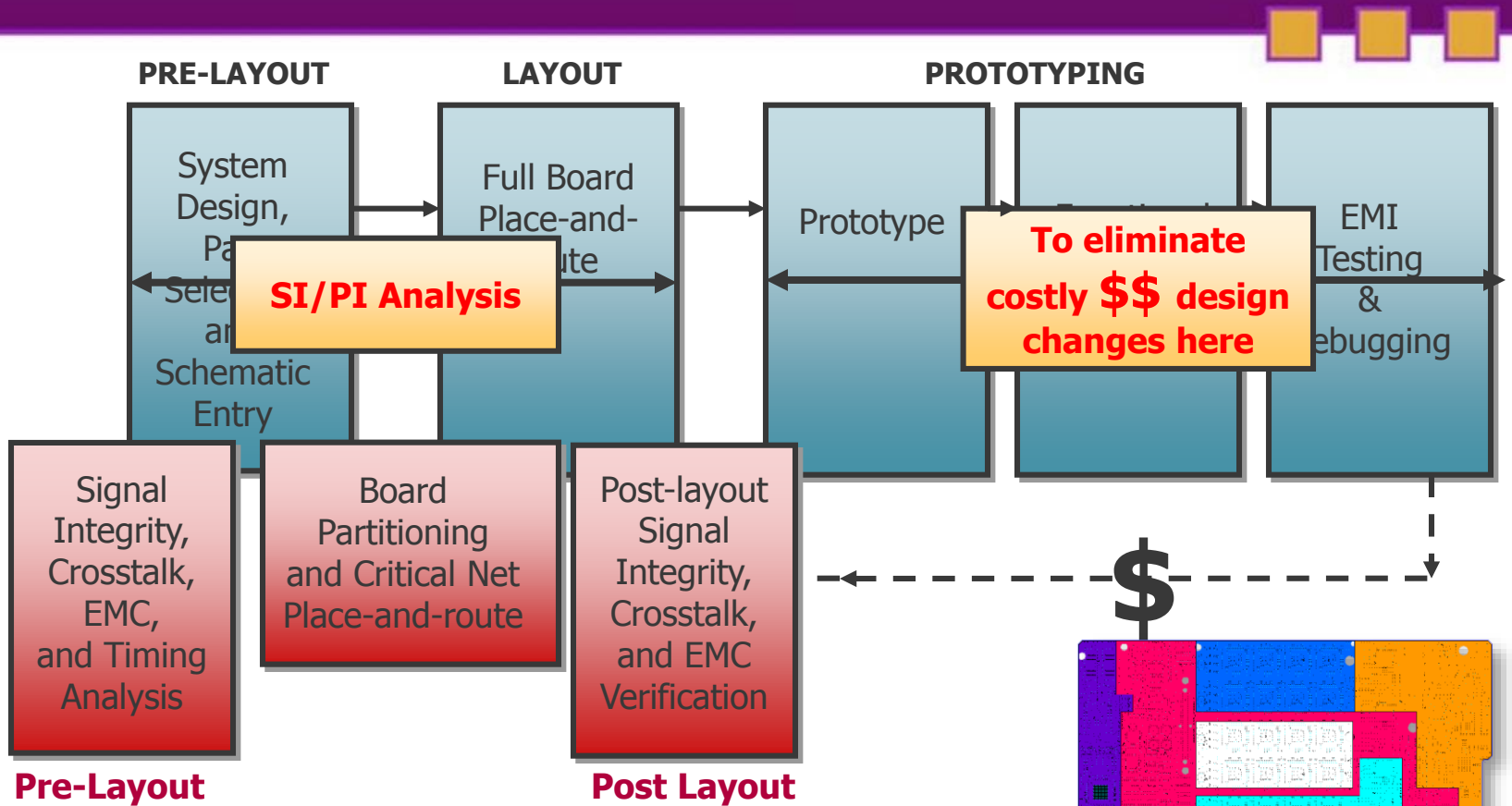
* Data based on Technology Leadership Awards entry averages

■ Use of Advanced Technologies...

- HDI (40%), RF/Microwave (26%)
- Flex/Rigid Flex (9%), Chip-On-Board (11%)



SI/PI Analysis in the Design Flow

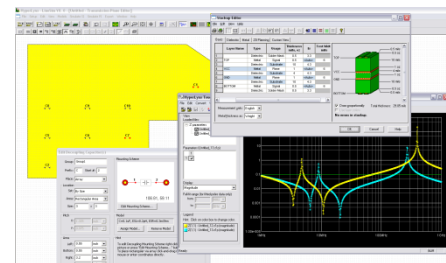
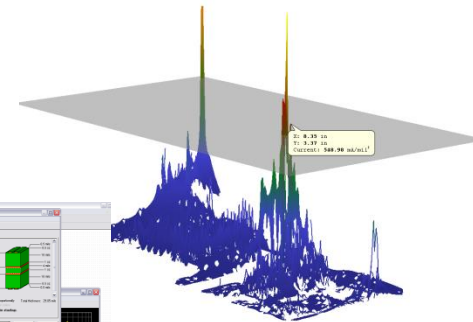
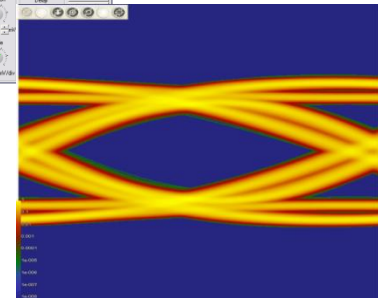
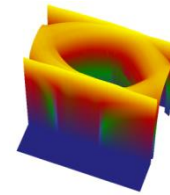
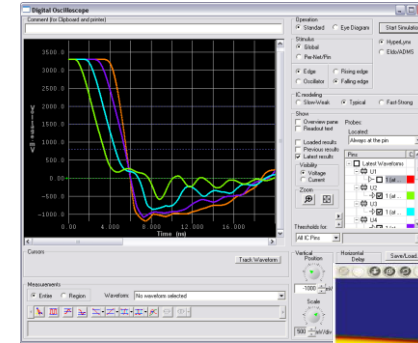


Design Constraints
 Technology Investigation
 Routing (topology) Options
 Stackup Definition

Design Verification
 Adhering to Constraints
 Finding Design Flaws
 Tuning Pre-emphasis and Equalization

High-speed PCB Design Issues

- **Signal Integrity**
 - General interfaces
 - Timing, crosstalk, signal quality
 - DDRx
 - Full STA, slew rate derating, write leveling
 - SERDES
 - Loss, impedance discontinuities, BER prediction
- **Power Integrity**
 - DC : do I have enough metal?
 - Voltage drop, high current density, neckdowns
 - AC : do I have enough caps? values?
 - Well-mounted? Good stackup?
 - Impedance profile, noise propagation
- **EMI/EMC**
 - Emission Regulations



Setup/planning – Board Stackup Design

- **Signal Integrity**

- **Impedance**

- Highest impedance will drive layer thicknesses
 - Need reference planes for uniform impedance

- **Loss**

- Drives trace widths → layer thicknesses

- **Crosstalk**

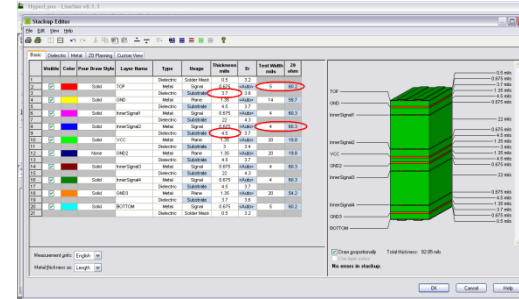
- Drives spacing requirements and routing density

- **Power Integrity**

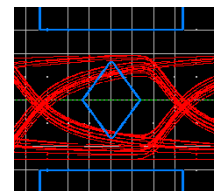
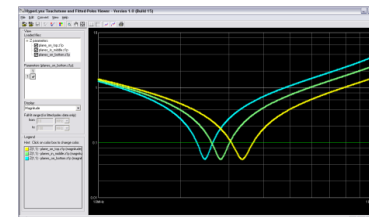
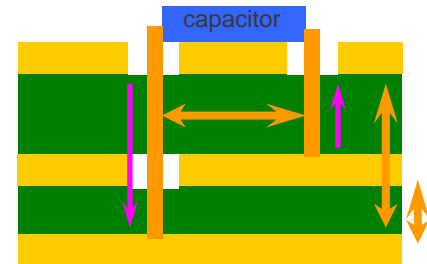
- Need enough **thick** planes to minimize DC drop
 - Need **closely-spaced** plane pairs for AC needs
 - Need stitching **vias** to relieve current choke points

- **EMI/EMC**

- Need **solid** reference planes throughout stackup



Layer Name	Usage	Thickness mils	Er	Diff Z0 ohm	Width mils	Gap mils	Z0 Curve
1	Solder Mask	0.5	3.2				
2	TOP	Signal	0.675	<Auto>	100	6	6.975
3		Substrate	3.7	3.6			
4	GND	Plane	1.35	<Auto>	100	14	12.027
5		Substrate	4.5	3.7			
6	InnerSignal1	Signal	0.675	<Auto>	100	5	9.581
7		Substrate	22	4.3			
8	InnerSignal2	Signal	0.675	<Auto>	60	4.5	4.160



Design Considerations

- **Layout/Route**

- Avoid crossing **splits** in reference planes (discontinuities)
- Minimize Inter Symbol Interference (**ISI**) using matched Impedances
- Minimize **Crosstalk** by isolating sensitive bits (ie. Strobes)
- Match traces within byte lanes (DQ, DM, DQS) to minimize **skews**



- **Power Supplies**

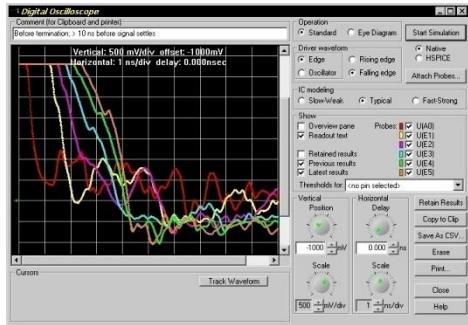
- Use precision resistors for V_{REF}
- Short/Wide traces to minimize **L** and **loss**
- 15~25mil clearance from V_{REF} to adjacent traces to minimize **coupling**
- **Decouple** high frequency Power Supply noise w/caps

- **Signaling**

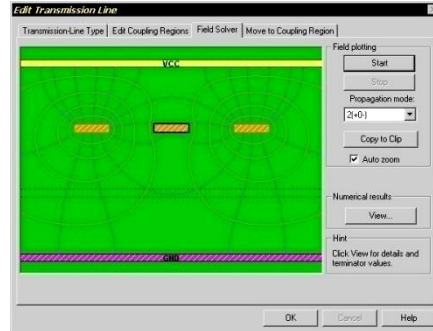
- DQ Driver Impedance Matching with proper drive strengths
- **ODT** is a must for better Signal Integrity (if not used then use T-branches or dumping resistor to minimize reflections)
- Choose termination carefully to balance **power consumption**, **signal swing**, and **reflection**
- Use **2T** timing for Address/Command



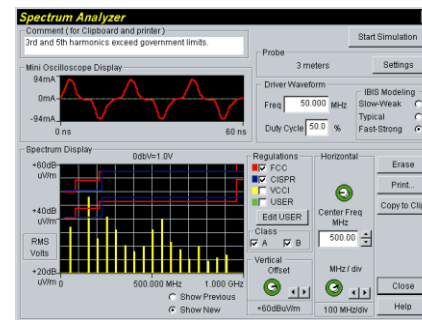
Signal Integrity Analysis



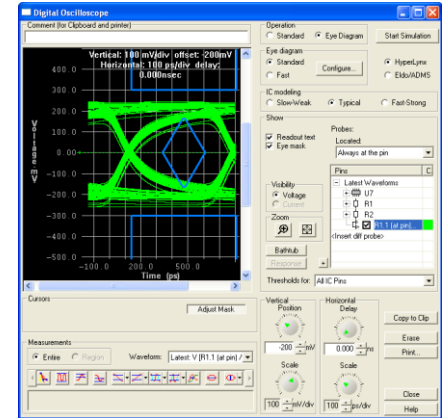
Signal Integrity



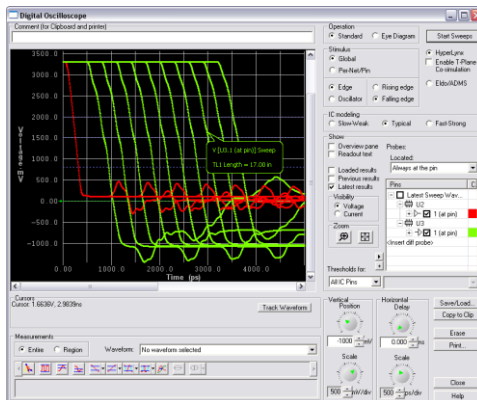
Crosstalk



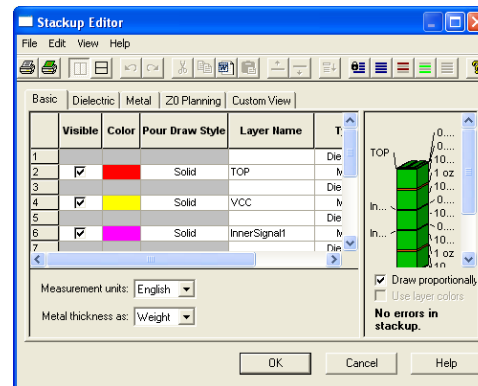
EMC



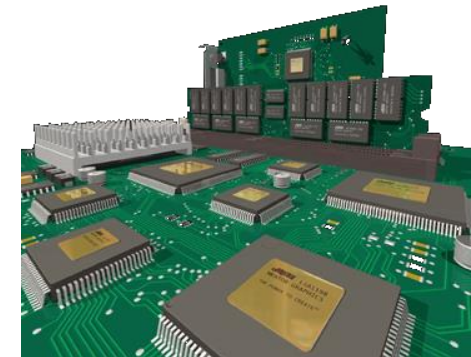
Eye Diagrams



Sweep Parameters



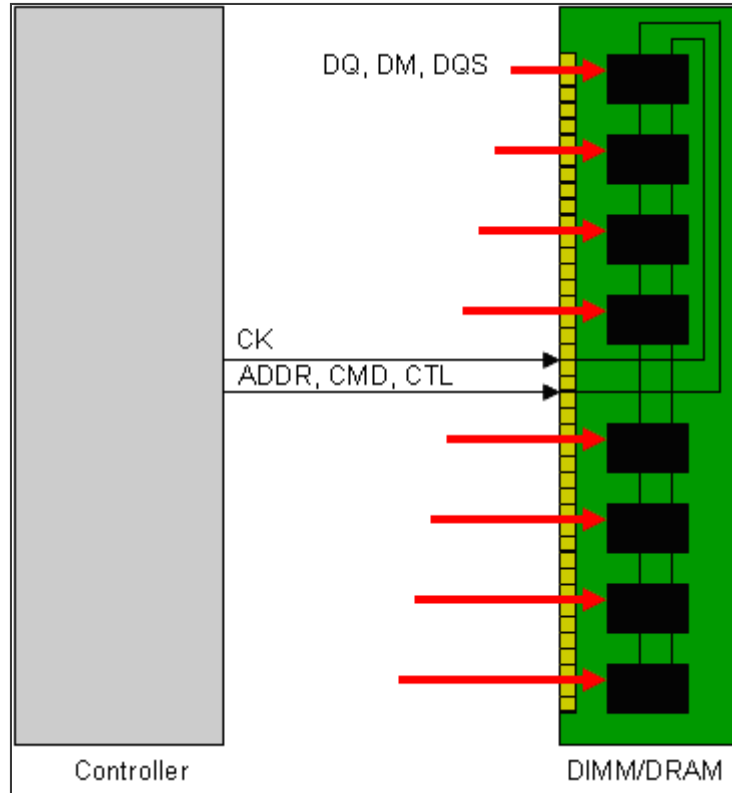
Impedance/Stackup Planning



Multi-Board

DDRx Fly-By Topology – Write Leveling

- Controller Delays DQ signals internally
- DQ & DQS signals are sent “Level” with the Addr/CLK



Overview – DDR3 vs. DDR4

	DDR3	DDR4	Comments
VDD/VDDQ/VPP	1.5/1.5/NA (1.35/1.35/NA)	1.2/1.2/2.5	Up to 20% power saving
Clock Frequencies	400-1600MHz	800-1600MHz+	Higher BW
CAS Latency	5~14	9~24	
Vref	VDDQ/2 (Ext)	Internal	
DQ Validation	Setup/Hold	Data Eye	Borrowed from SERDES
Data Termination	VDDQ/2 (VTT)	VDDQ	Asymmetric Term.
Add/Cmd/Termination	VDDQ/2 (VTT)	VDDQ/2	
I/O Standard	SSTL15	POD12	Power savings on “1” bits
On Chip Error Detection	No	Parity (Cmd/Add) CRC (DQ)	Server Class
Bank Grouping	No	4	“Ping-Pong” for efficient use



Overview – LPDDR3 vs LPDDR4

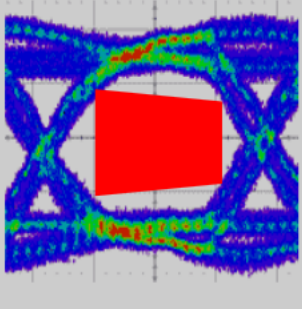
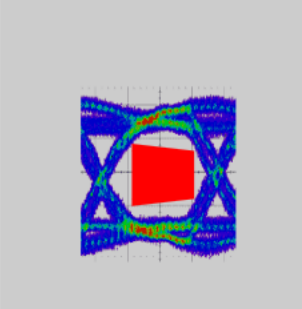
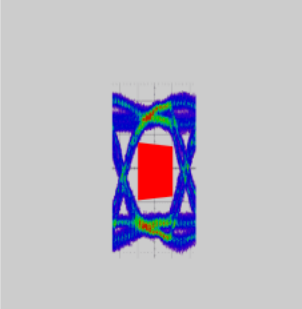

	LPDDR3	LPDDR4	Comments
CLK	400-800MHz	800-1600MHz	2x speed (possibly more)
Bandwidth	12.8GB/s (2ch)	25.6GB/s (2ch)	Higher BW
VDD2/VDDQ/VDD1	1.2/1.2/1.8	1.1/1.1/1.8	Power reduced 10%
I/O Interface	HSUL	LVSTL	40% I/O Power reduction vs. POD
DQ ODT	Vtt Term	VSSQ Term	
CA ODT	No term	VSS Term (optional)	
Vref	External	Internal	

- DDR4 to use **P**seudo **O**pen **D**rain (POD)
 - Address, Command, Control continue to be SSTL
- LPDDR4 to use **L**ow **V**oltage **S**wing **T**erminated **L**ogic (LVSTL)
 - Both Data and Address



Overview – Speed related Eye challenges

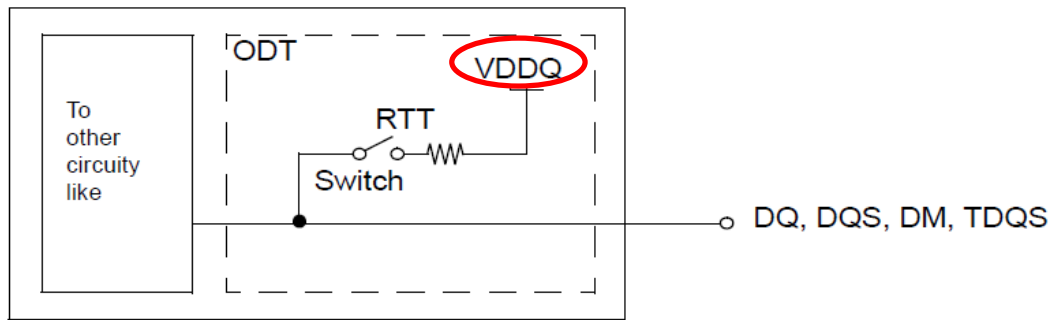
Mode	LPDDR1	LPDDR2	LPDDR3	LPDDR4
Data Rate	400Mbps	800Mbps	1600Mbps	3200Mbps
tCK	2.5ns	1.25ns	0.625ns	0.3125ns
Data eye area (Normalized)	14	1	0.5	0.09

Mode	LPDDR1	LPDDR2	LPDDR3	LPDDR4
Data eye area (Normalized)				

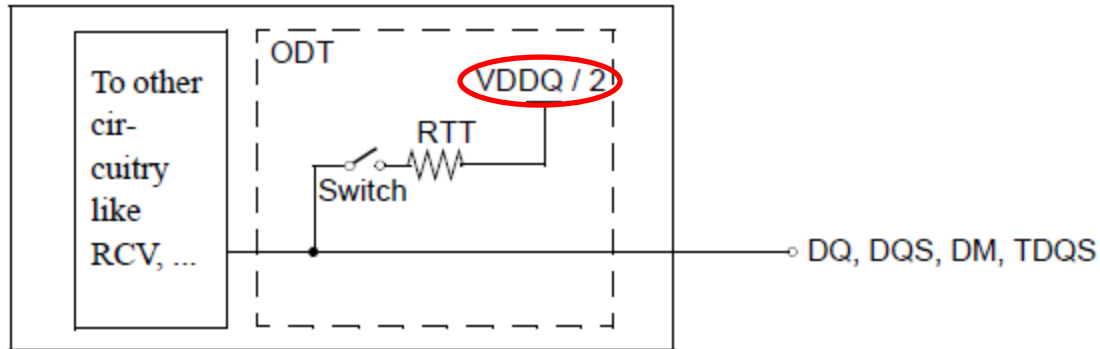
Semicon West: High Performance & Low Power Memory Trends – SK Hynix



New Drive Standards – Difference



DDR4

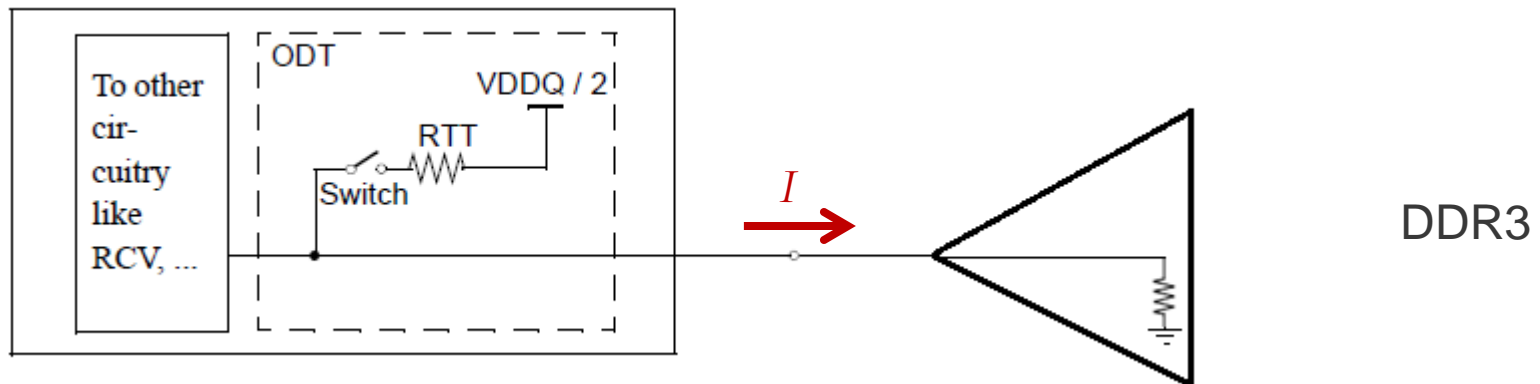
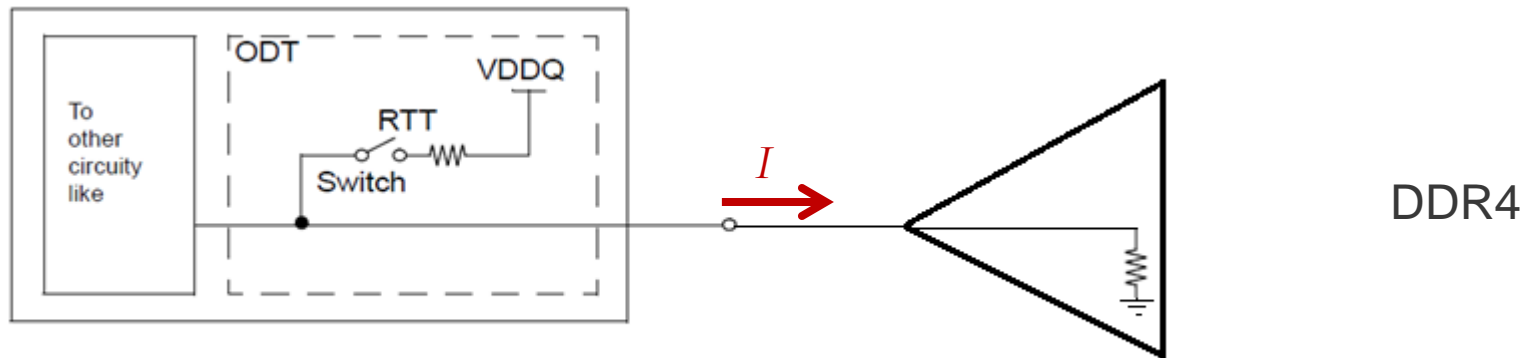


DDR3



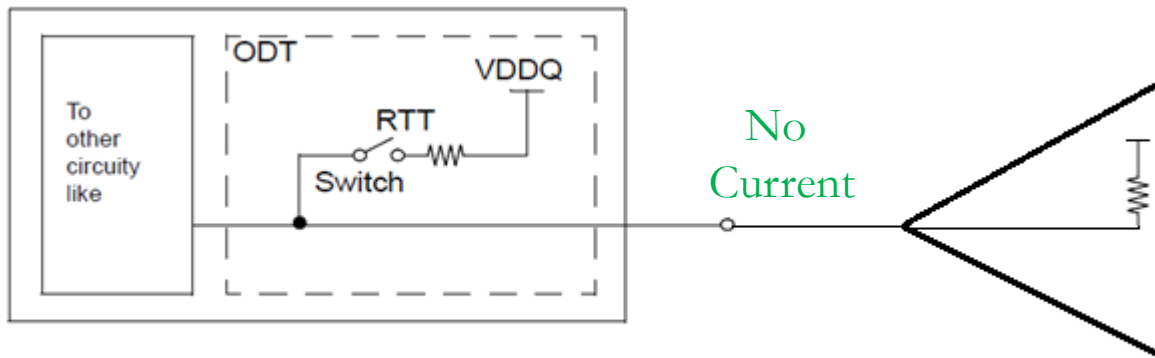
New Drive Standards – Why?

- Current still flows when driving low

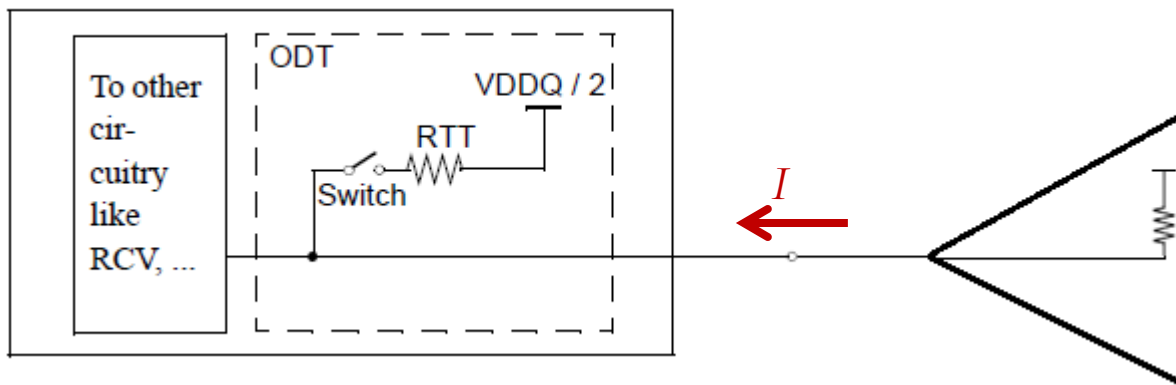


New Drive Standards – Why?

- No current draw when driving a high



DDR4

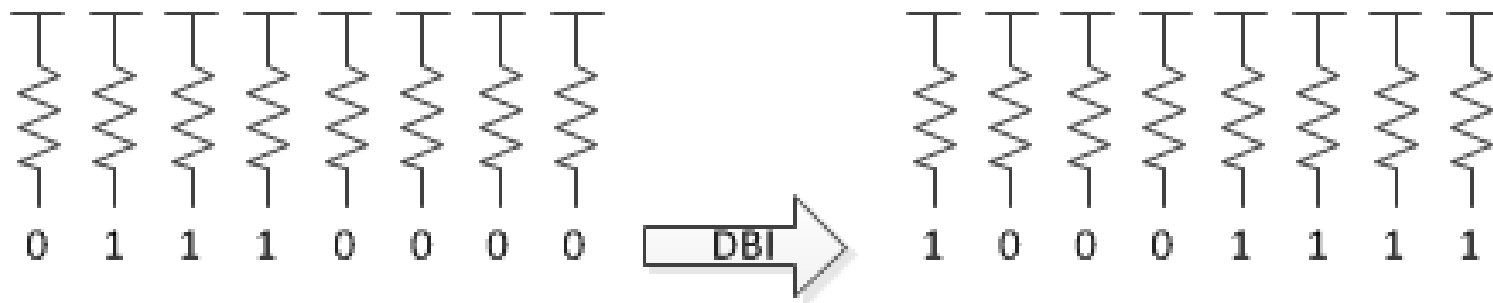


DDR3



Power Savings with DBI

- Ensure more 1's than 0's with POD
- If more than 4 bits in a byte are 0, toggle bits
- DBI (Data Bit Inversion) shared with DM => only one feature enabled
- DBI pin is I/O (affects both reads and writes)



PreLayout SI Simulation

HyperLynx - LineSim v9.2 - [DDR3_AISignals.fcs <C:\Mentor_AE\Nitin_B\DDR_Workshop\Lab1>] - Free-Form Schematic Editor

File Setup Edit View Models Simulate SI Simulate E Export Window Help

Output

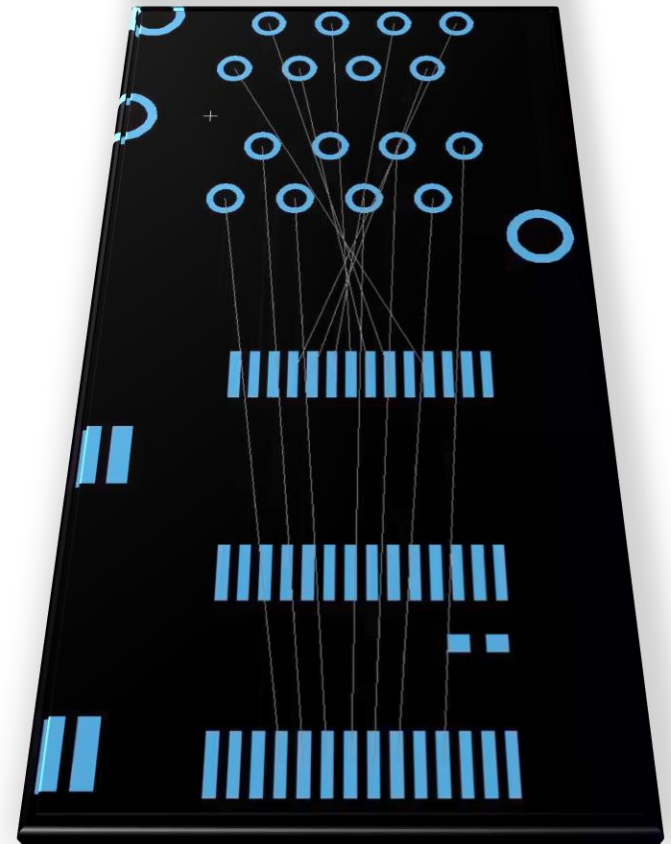
:: Warning: The sum of the maximum clamp curves is not monotonic at voltage -2.4.
Success : Parse succeeded on file C:\Mentor_AE\Nitin_B\DDR_Workshop\Lab1\v89c_lp5.ibs.

X=020.050, Y=004.900 in CAP_NUM

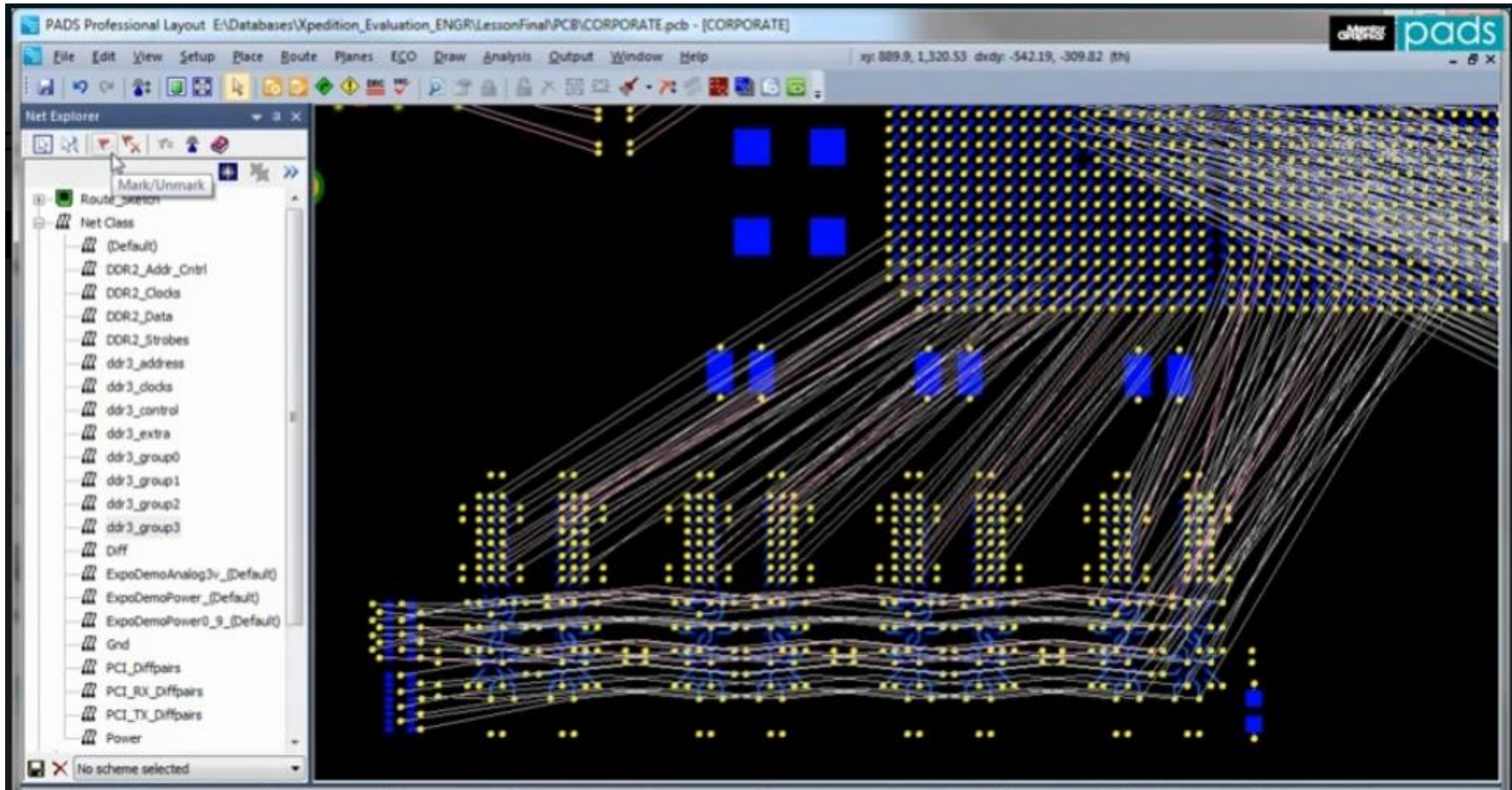


DDRx Routing Guidelines

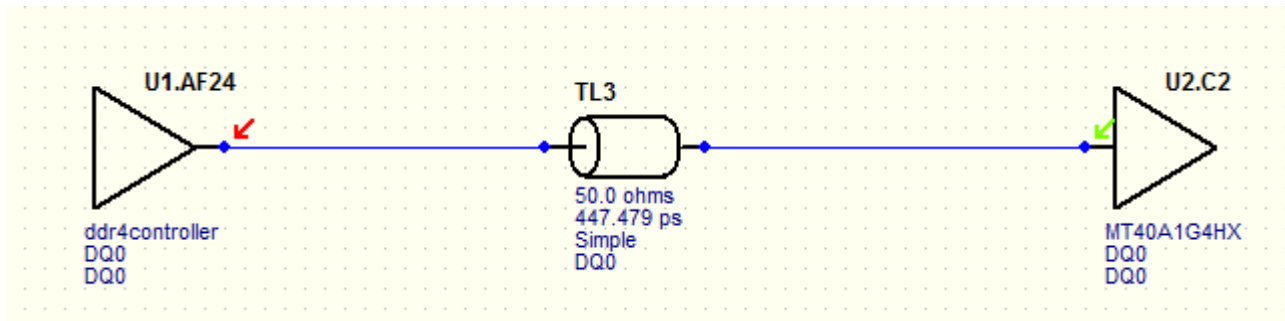
- Constraint-driven routing
 - Designer knows where the traces should be routed
 - Precise location of traces & vias
 - Control style of routing incl serpentines
 - Things to observe while routing DDRx
 - Width & clearance rules
 - Placement intentions
 - Netline organization
 - Layer restrictions
 - Pad/via entry rules (angle, size)
 - Diff pair rules



Using Sketch routing with DDR3 (video)



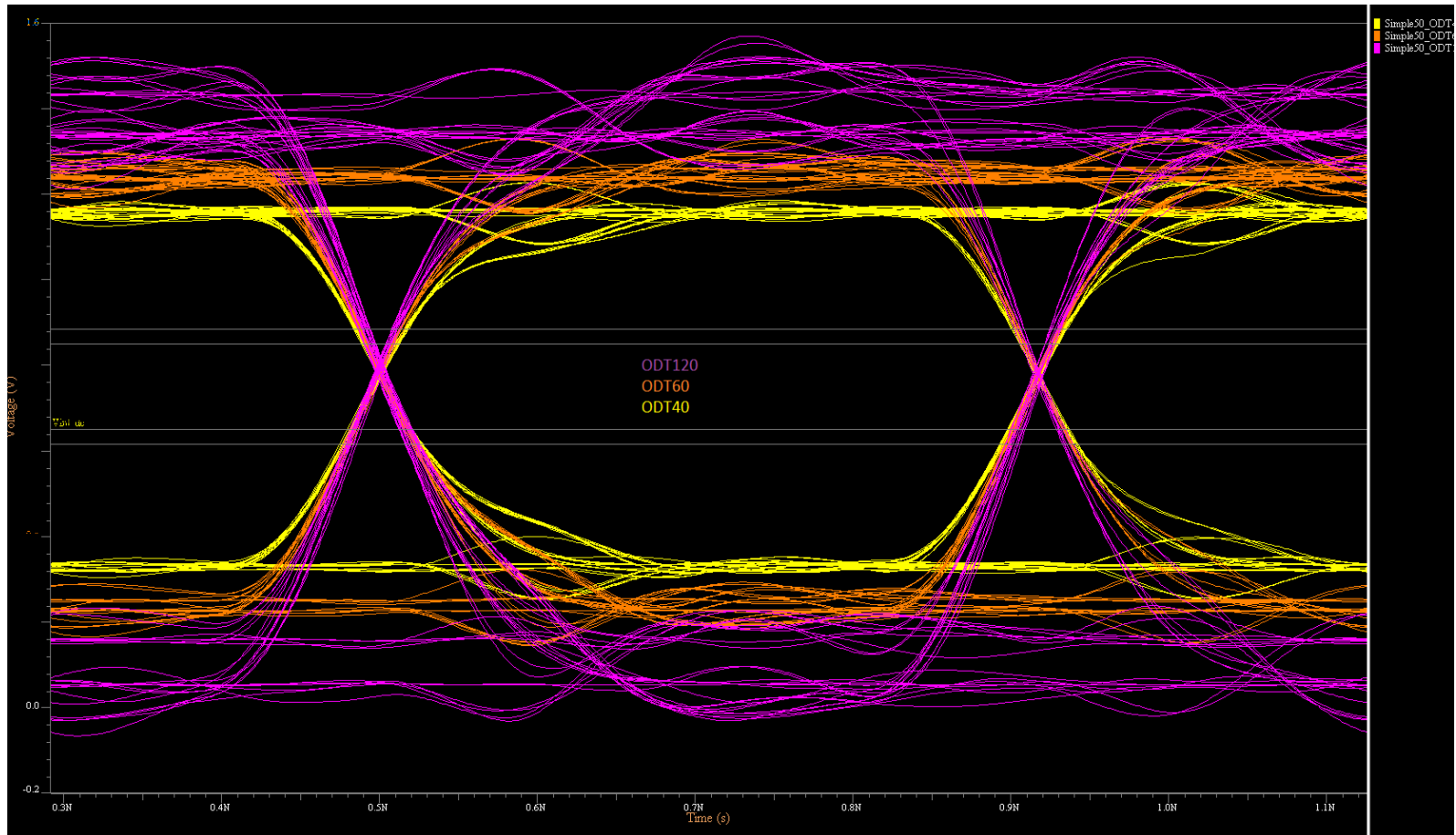
Simple Comparison



- Controller -> 50 Ohm T-Line -> DRAM
- Vary DRAM's ODT to see center level of eye
- 2400Mbps Data rate



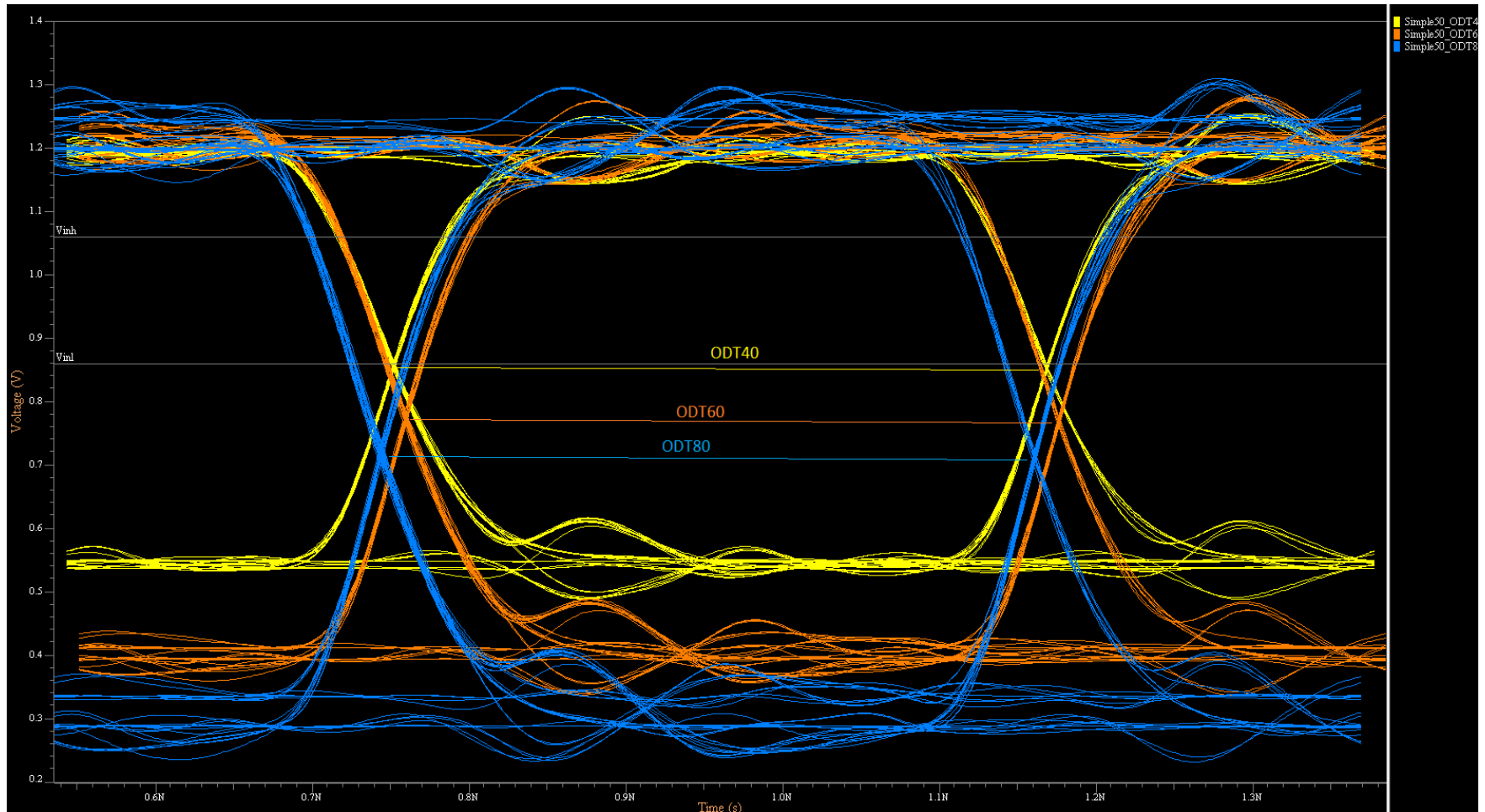
DDR3 – sweeping Rx ODT



No change in Center of Eye with ODT



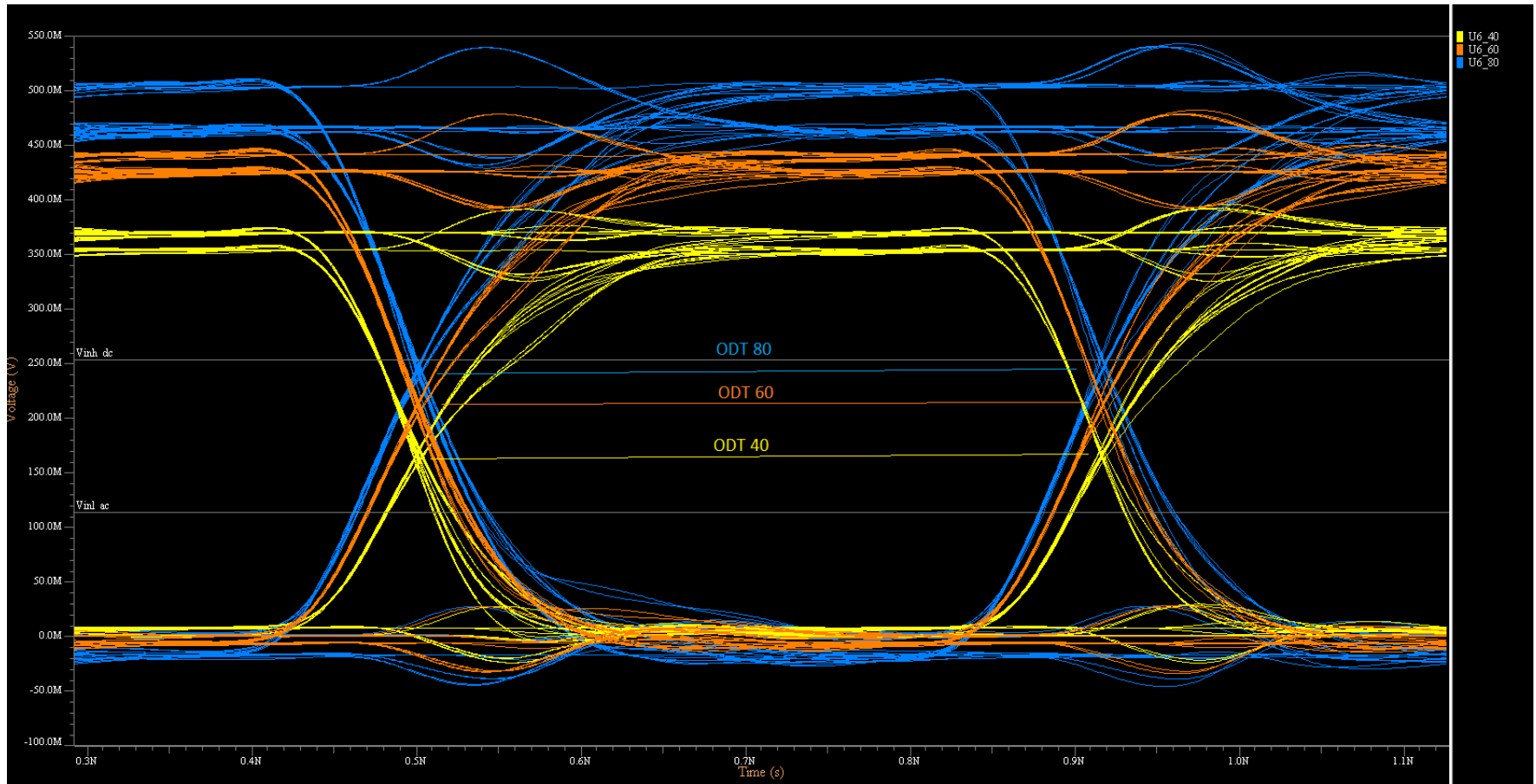
DDR4 – Eye shifting



Eye center shifts with ODT change



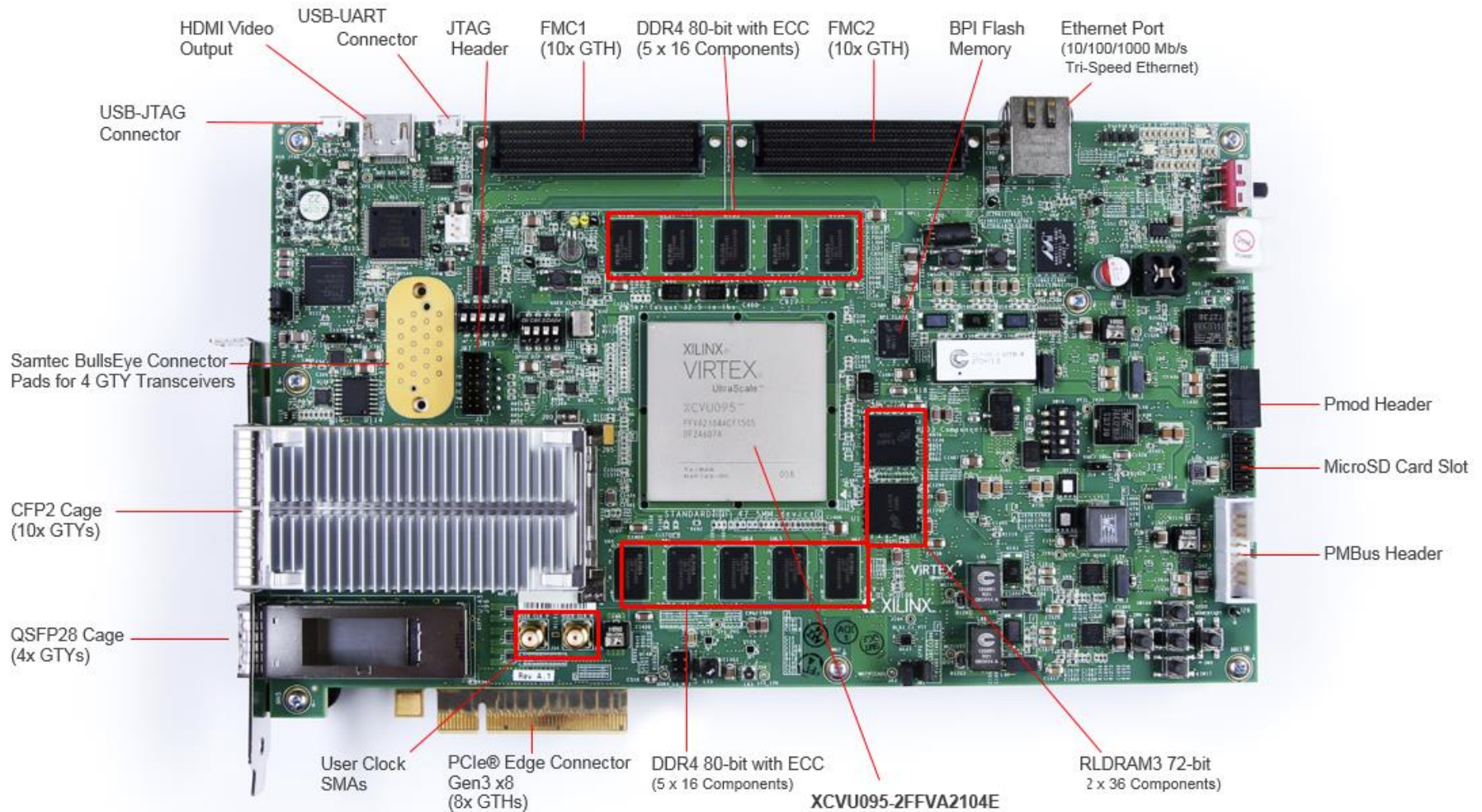
LPDDR4 – Eye shifting



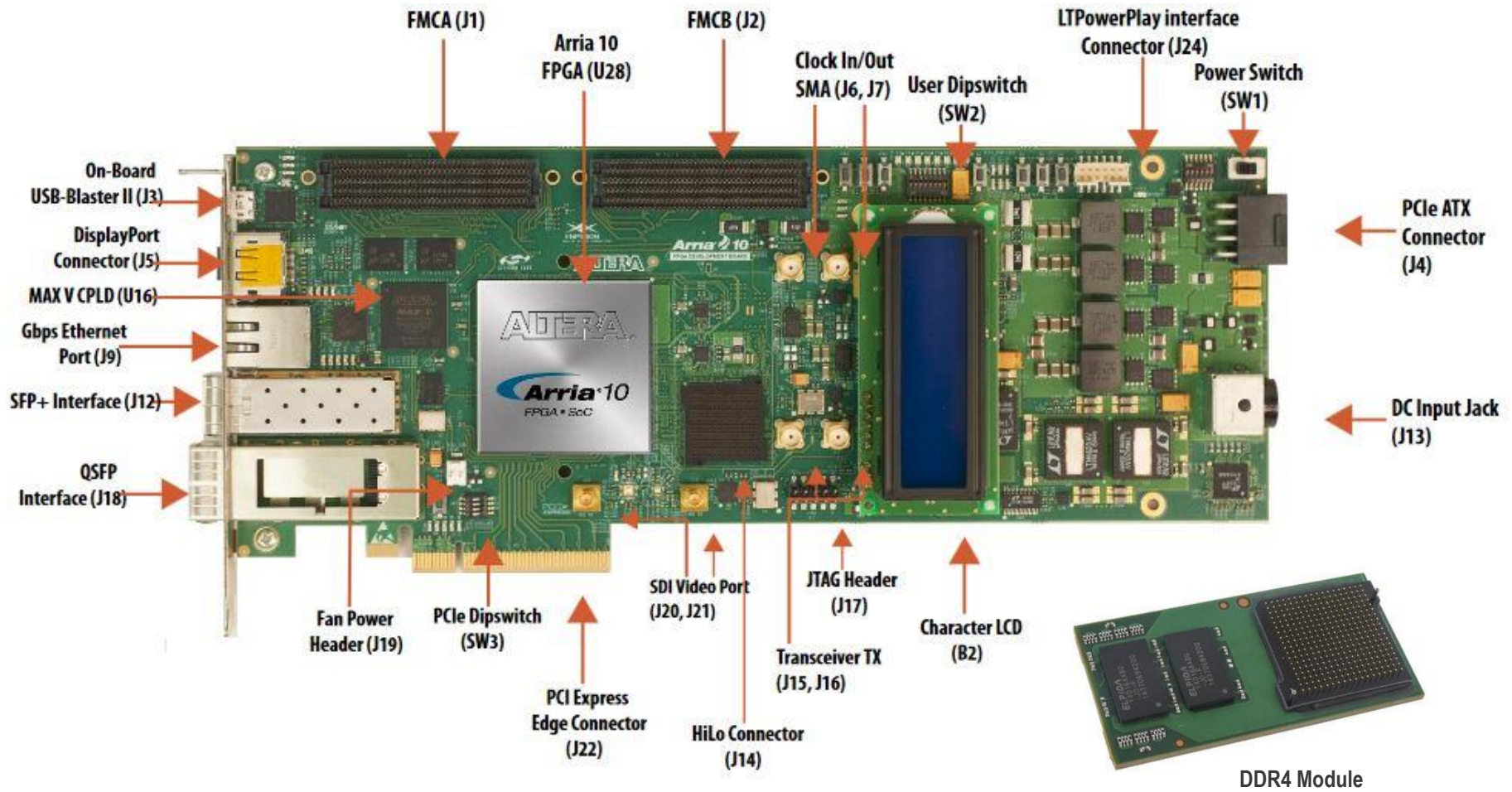
Eye center shifts with ODT change



Xilinx VCU108 UltraScale Dev Board

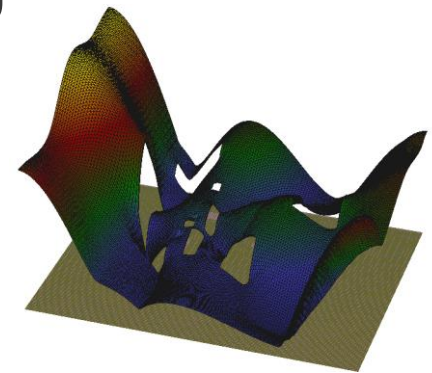
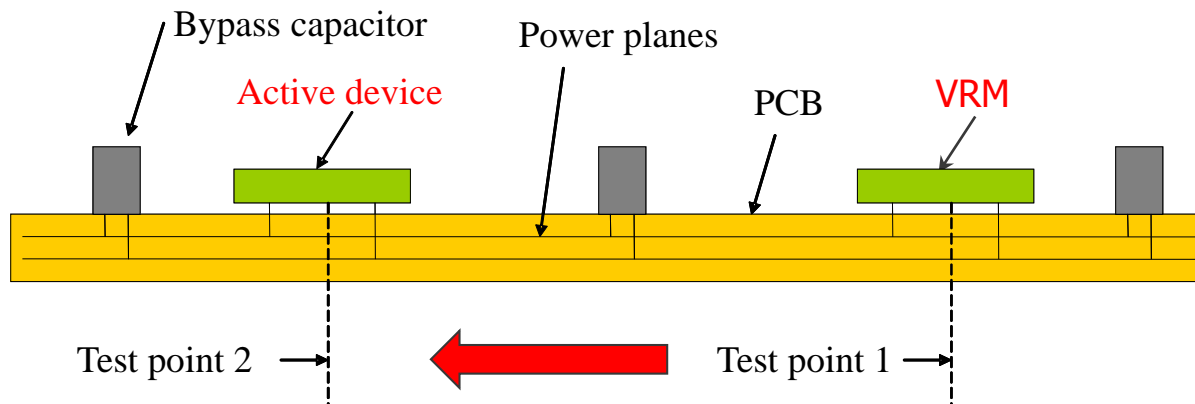
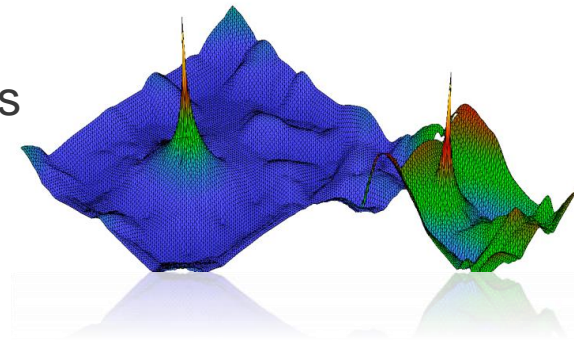


Altera Aria10GX FPGA Dev Board



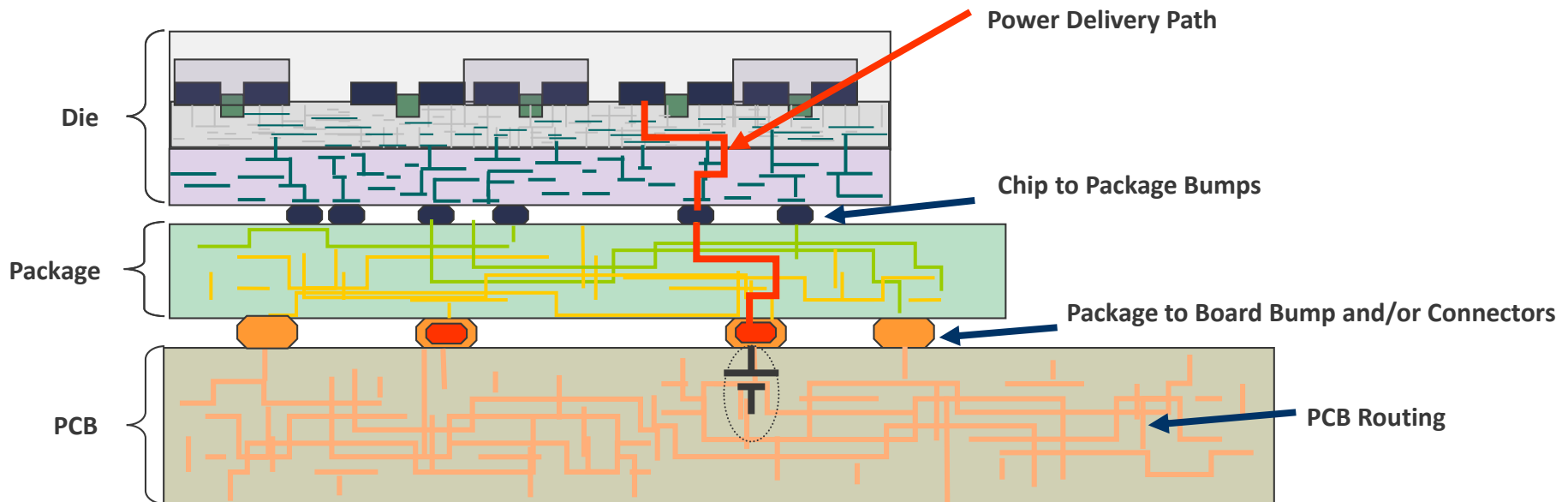
What is Power Integrity?

- What is a Power Distribution Network (PDN)?
 - The path (or **interconnects**) from PWR to ICs (Active Devices)
 - Including PCBs and packages
 - Planes, routed traces, and decoupling capacitors
- Deliver adequate power from DC->HF
- Minimize EMI issues
- Provide low-noise reference path for signaling



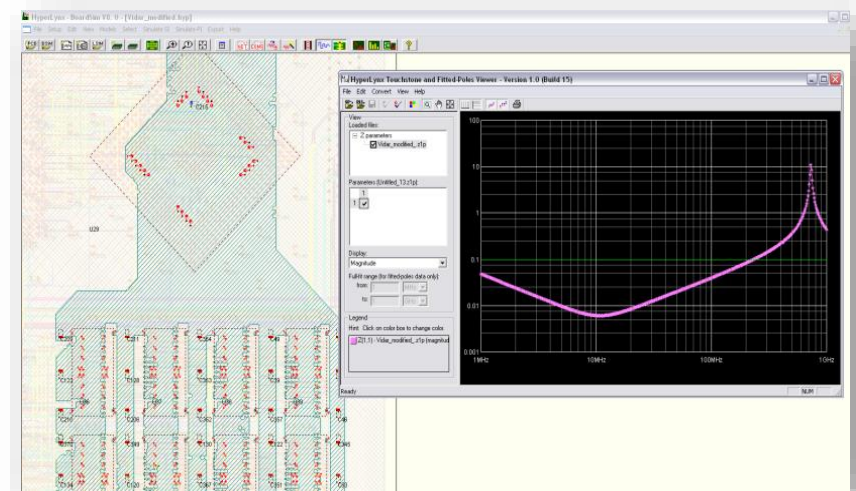
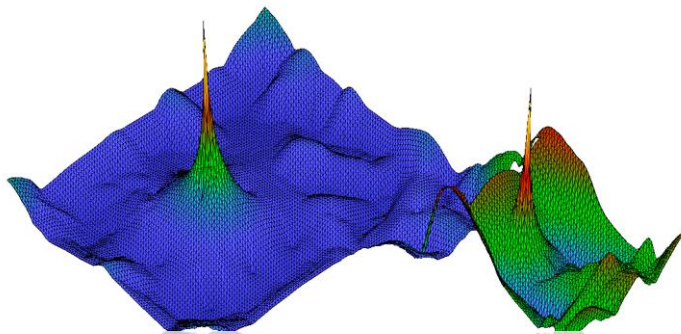
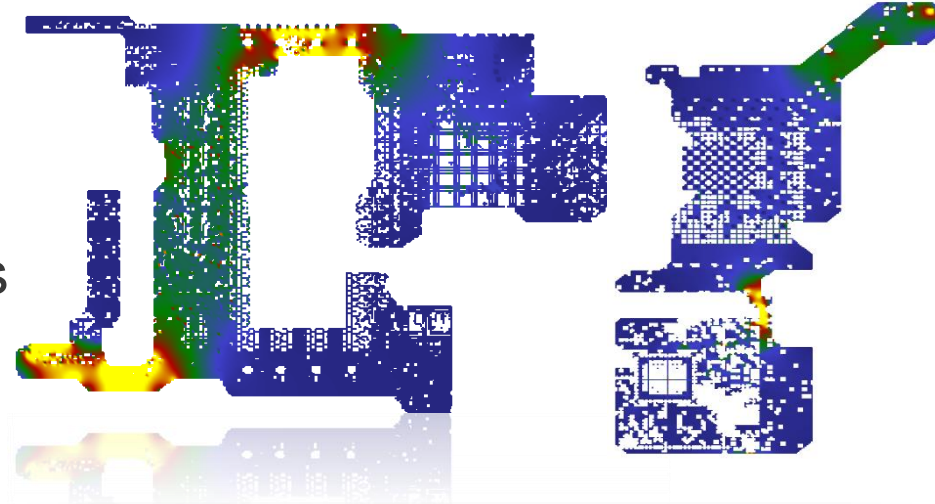
Plane Design & the PDN

- Meeting Power Integrity requirements
 - Design PDN (path from power supply to ICs) of **low impedance**
 - As if an ideal voltage source were directly connected to ICs
 - Use impedance to **represent** and **measure** PDN quality



Power Integrity Analysis

- **DC Drop Analysis**
 - Excessive **Voltage Drop** & High **Current Densities**
 - Batch Analysis of Supply Nets
- **AC Power Plane Analysis**
 - Capacitor **Selection/Mounting**
 - Power Supply **Impedance**
- **Plane Noise Analysis**
 - Voltage **Ripples**



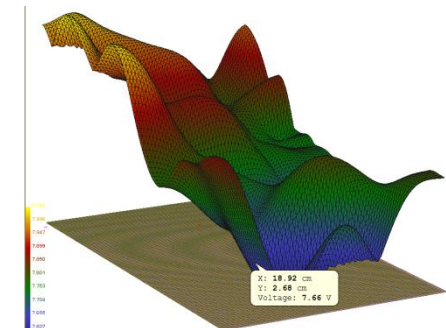
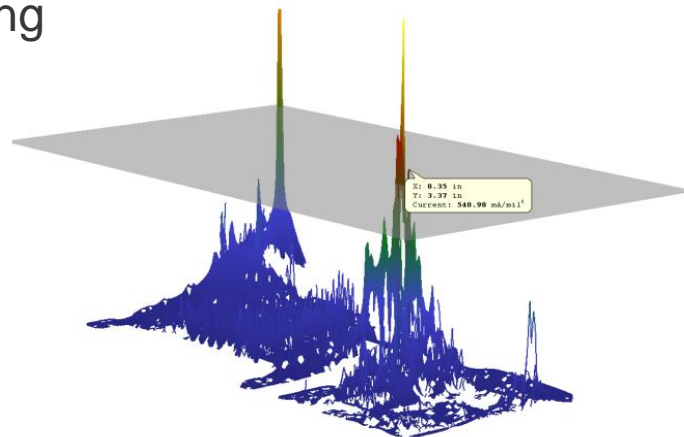
Power Integrity Optimization (Why?)

■ Reduce Product **Costs**

- Minimizing capacitor BOM (more Caps is worse)
- Reducing PCB size and layer count
- Eliminating design iterations
 - Up-front PDN planning & Improve time-to-results

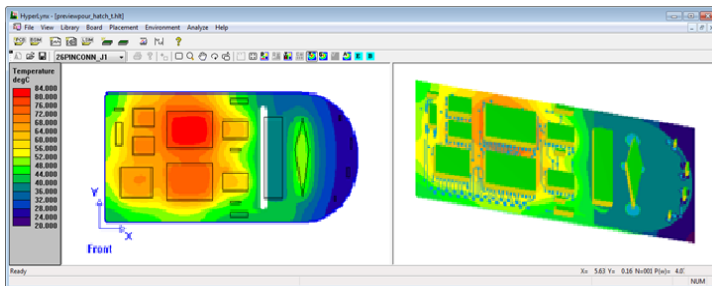
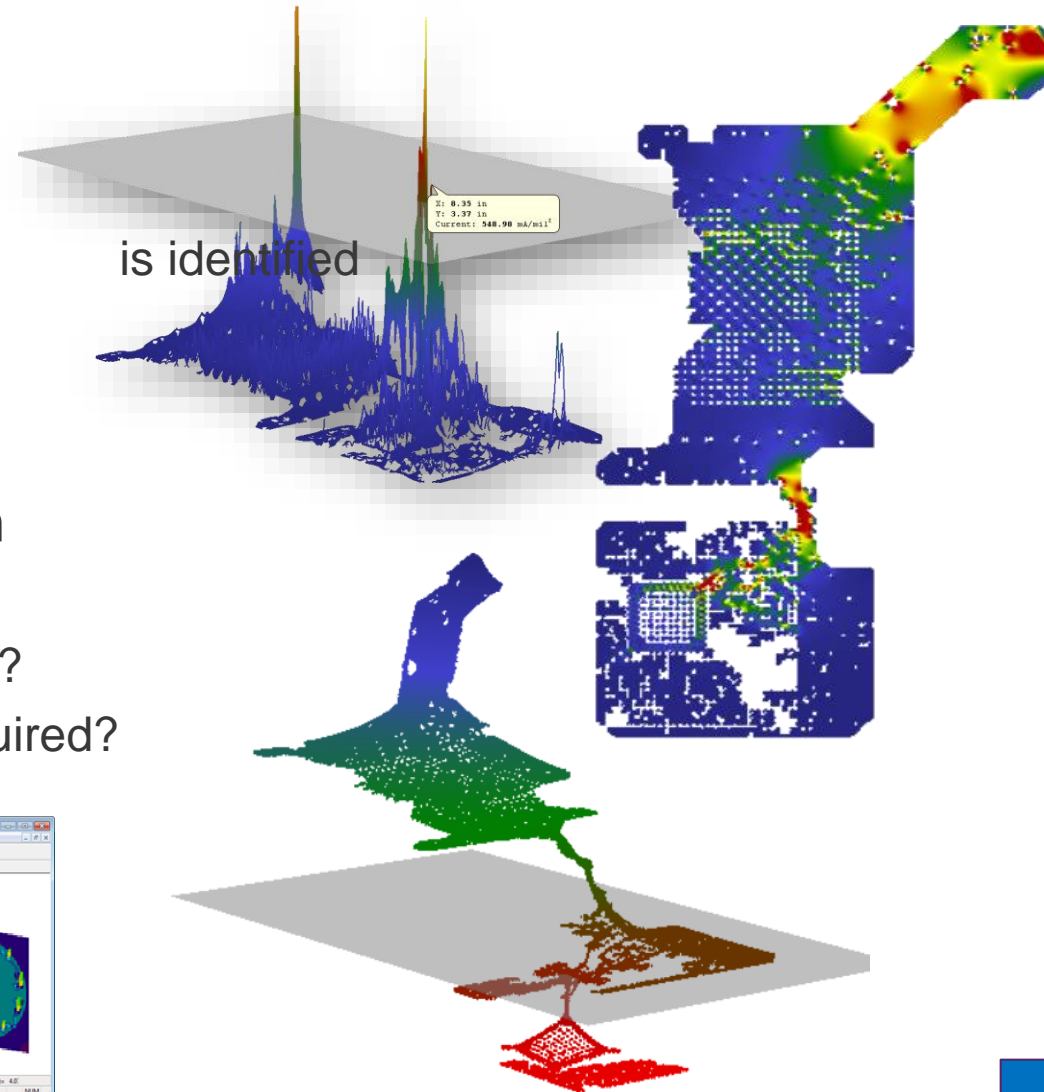
■ Improve Product **Reliability**

- Identifying excessive voltage drop and high current densities at DC
- Providing stable AC power through capacitor decoupling



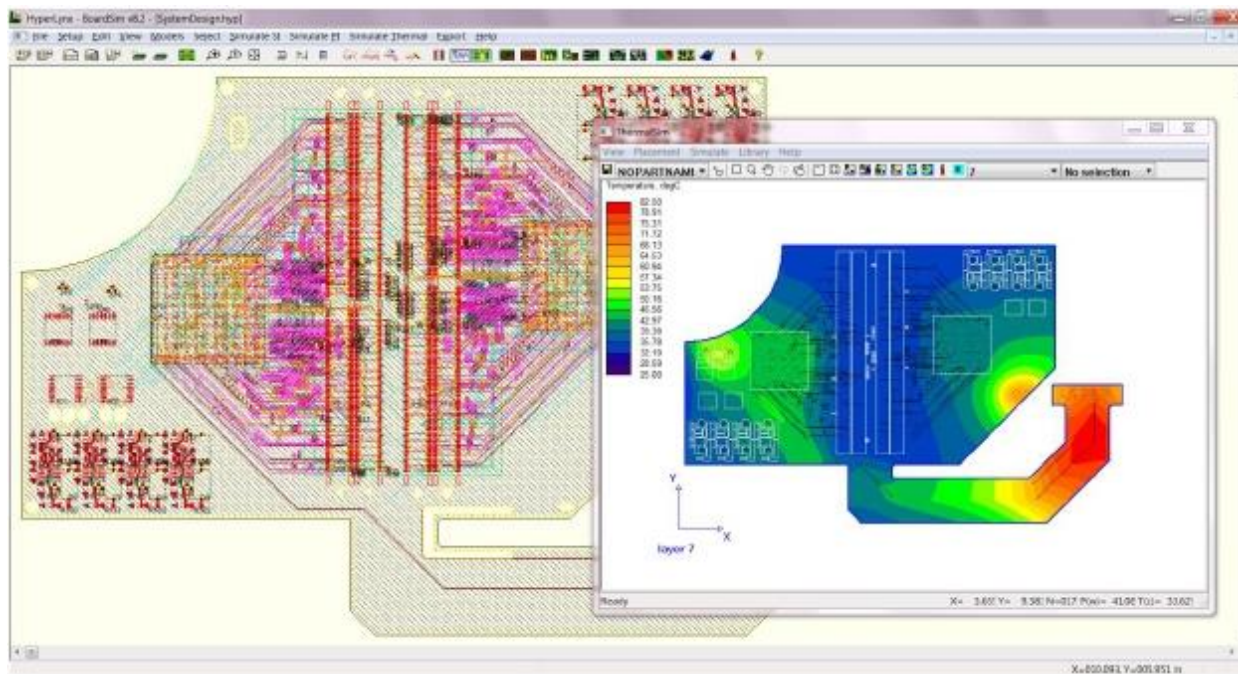
DC Drop and Thermal Analysis

- Identify Failures Easily
 - Voltage drop magnitude is easily measured
 - Excessive current density clearly
 - Determine if current density is causing thermal failure
- Create an Optimized Solution
 - How much copper is needed?
 - Optimize component placement?
 - Are additional stitching vias required?



Power Integrity/Thermal Integrity Effects

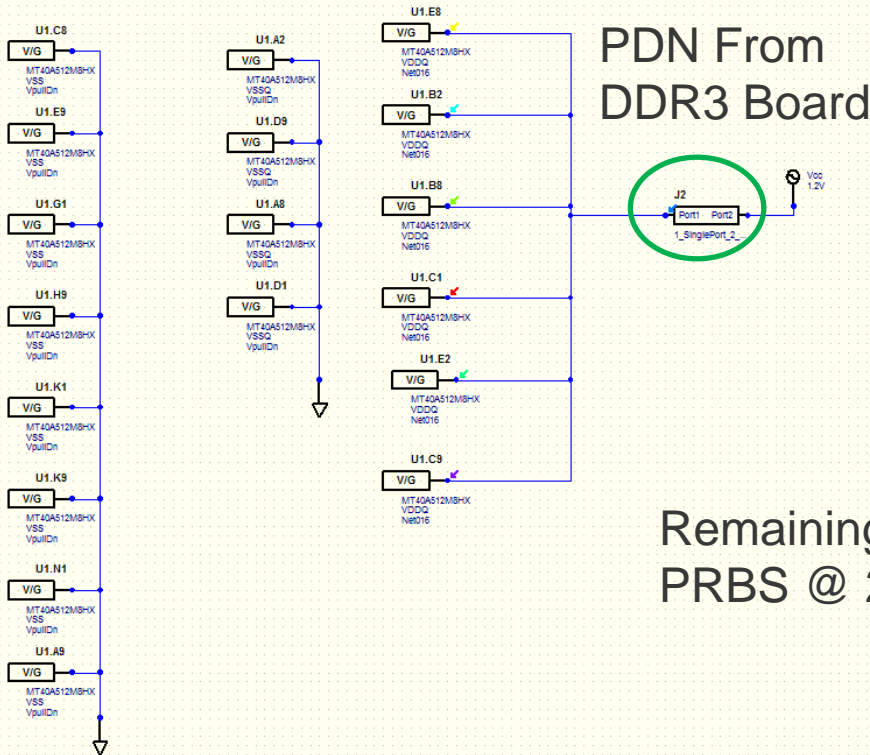
- Analyze **Joule Heating** effects in traces
 - Identify/localize sensitive area on board
 - Minimize field failures and increase product reliability



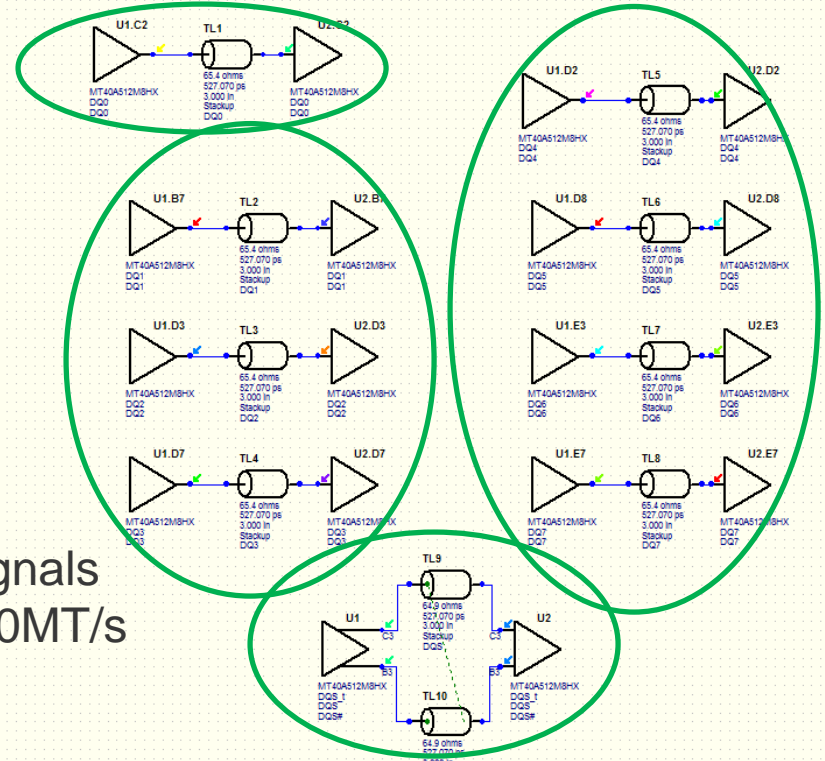
Power Integrity Effects



Power Integrity Effects from DDR3 switching



Signal held high

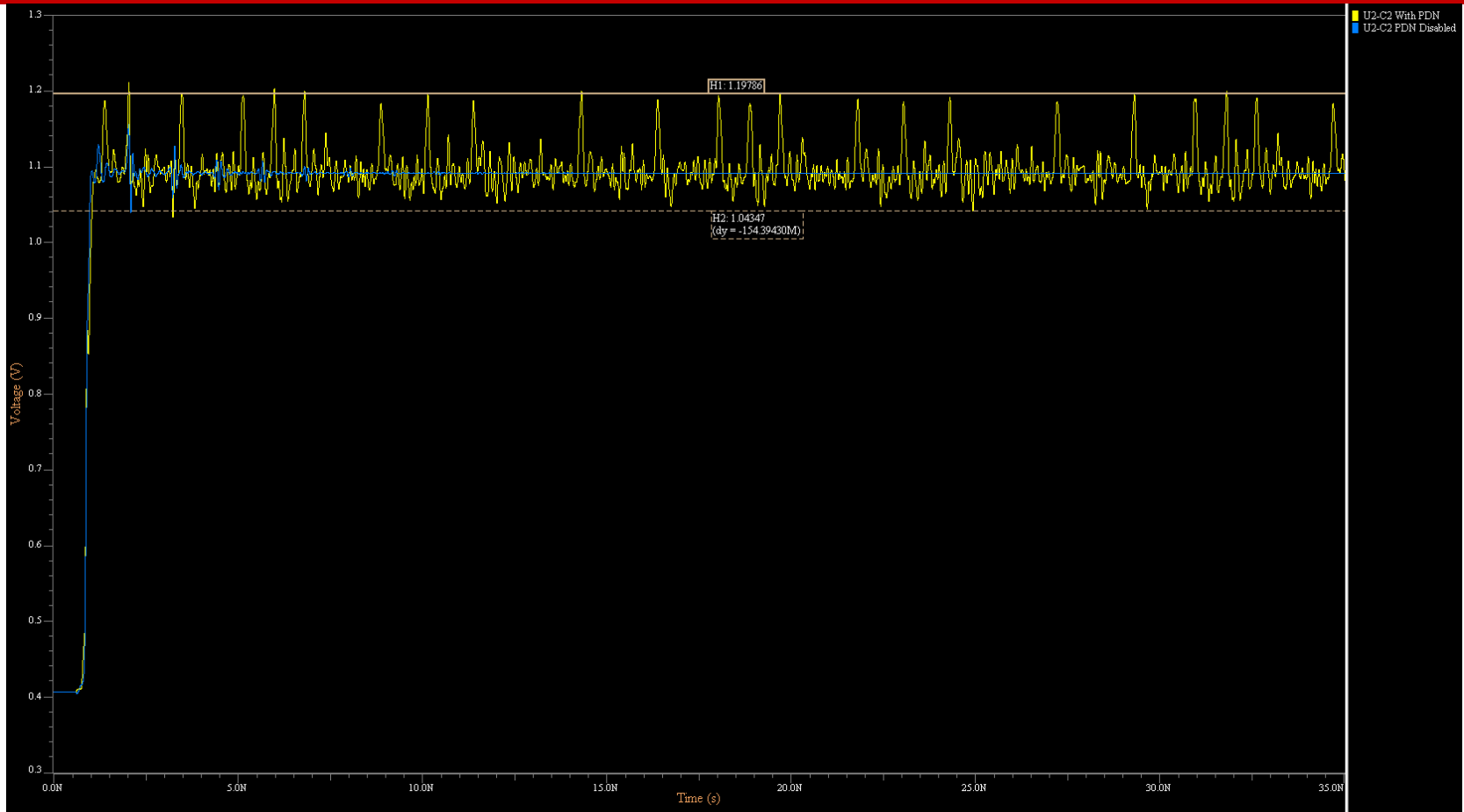


Remaining signals
PRBS @ 2400MT/s

DQS clock @ 1.2GHz



Power Integrity Effects from DDR3 switching

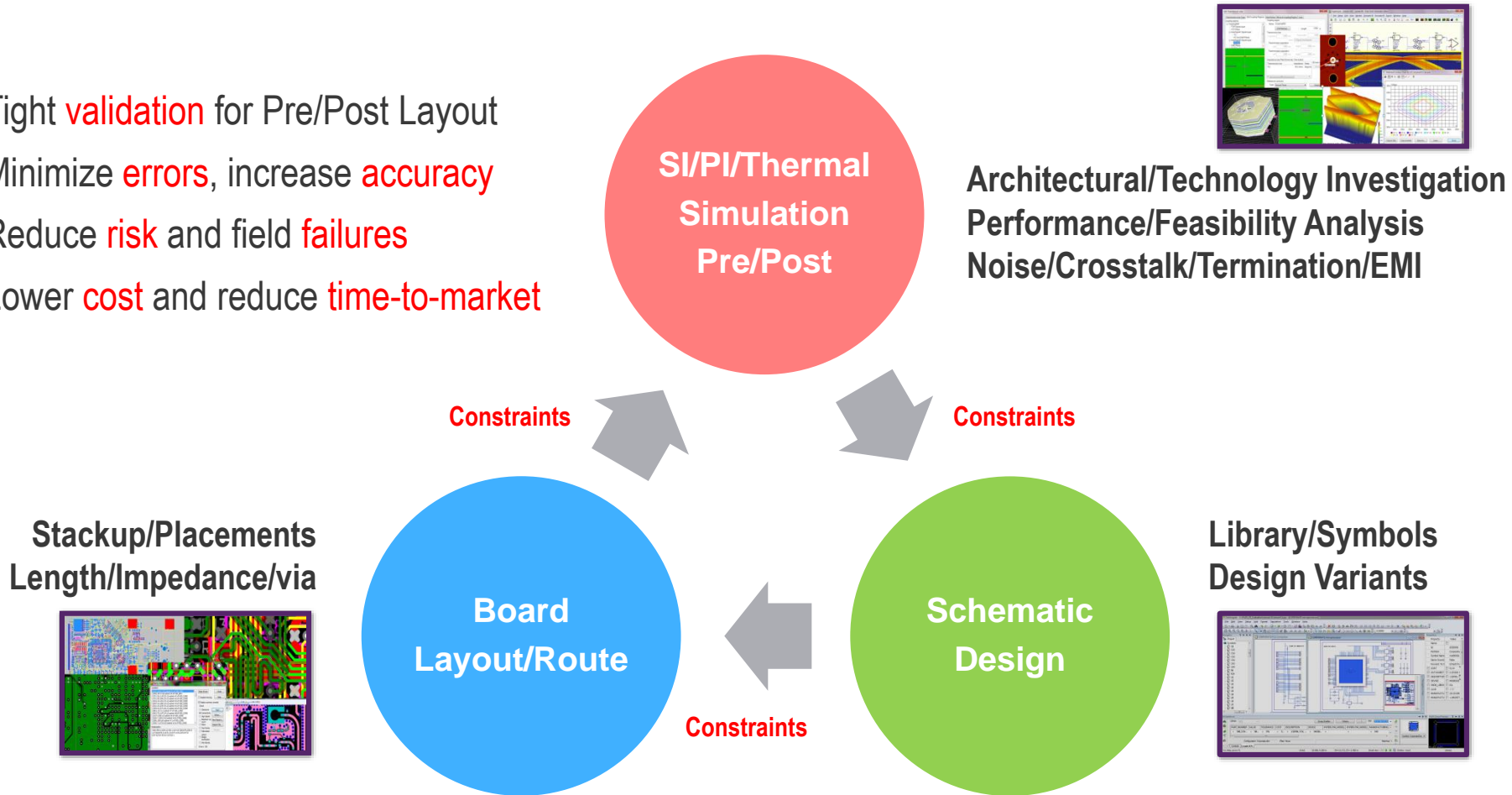


150mV noise from switching of other bits in lane



Integrated Design Flow

- Tight **validation** for Pre/Post Layout
- Minimize **errors**, increase **accuracy**
- Reduce **risk** and field **failures**
- Lower **cost** and reduce **time-to-market**



Contact Info



EDA Direct Inc.
(408) 496-5890
(888) 669-9EDA

To enroll for our upcoming seminars, workshops, training classes,
and view demo videos of our products

visit www.edadirect.com

